## Notice of References Cited Application/Control No. 10/795,845 Applicant(s)/Patent Under Reexamination SWAMINATHAN, SIVAPRASATH Examiner Tanh Q. Nguyen Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,560,660 B1	05-2003	Flanagin, Stephen D.	710/15
*	В	US-6,317,798 B1	11-2001	Graf, John D.	710/15
*	С	US-2003/0126226 A1	07-2003	Ramey, Brian C.	709/215
*	D	US-2004/0034764 A1	02-2004	Bulusu et al.	713/1
*	E	US-5,790,895 A	08-1998	Krontz et al.	710/64
*	F	US-7,120,679 B2	10-2006	Remer, Eric B.	709/220
*	G	US-2005/0055486 A1	03-2005	Natu et al.	710/260
*	Ι	US-7,111,090 B1	09-2006	Lemke et al.	710/48
*	-	US-6,779,047 B1	08-2004	Caddes et al.	710/15
*	J	US-7,043,205 B1	05-2006	Caddes et al.	455/41.2
*	К	US-5,179,661 A	01-1993	Copeland et al.	710/29
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S			•		
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.